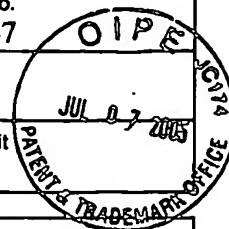


Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-185001	Application No. 10/730,047
	Applicant Shunpei Yamazaki et al.		
	Filing Date December 9, 2003	Group Art Unit 2822	

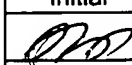

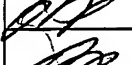
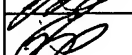
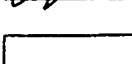


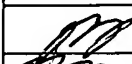
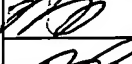
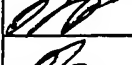
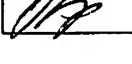
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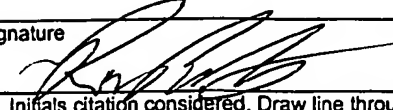
Examiner Signature 	Date Considered 12/27/05
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	AKK	Documents distributed in the " <i>13th Flat Panel Display Manufacturing Technology Expo & Conference</i> " by ELDis Group; July 2, 2003 (full translation)

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	AN							
	AO							
	AP							

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	AR	
	AS	
	AT	

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	AM							
	AN							
	AO							
	AP							

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